

**Search Notes**

Application/Control No.

10/531,884

Examiner

Karen Cheng

Applicant(s)/Patent under  
Reexamination

HAIGH ET AL.

Art Unit

1626

**SEARCHED**

Class	Subclass	Date	Examiner
514	422	7/17/2007	KC
548	517	7/17/2007	KC
548	518	7/17/2007	KC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
514	422	7/17/2007	KC
548	517, 518	7/17/2007	KC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search (including Interference, see attached)	7/17/2007	KC